



**ALPHA & OMEGA**  
SEMICONDUCTOR

**AON6370**

**30V N-Channel MOSFET**

### General Description

- Trench Power  $\alpha$ MOS Technology
- Low  $R_{DS(ON)}$
- Low Gate Charge
- High Current Capability
- RoHS and Halogen-Free Compliant

### Applications

- DC/DC Converters in Computing
- Isolated DC/DC Converters in Telecom and Industrial
- See Note I

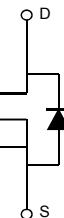
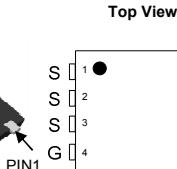
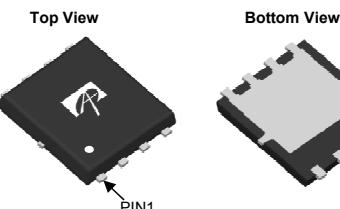
### Product Summary

$V_{DS}$	30V
$I_D$ (at $V_{GS}=10V$ )	47A
$R_{DS(ON)}$ (at $V_{GS}=10V$ )	< 7.2m $\Omega$
$R_{DS(ON)}$ (at $V_{GS}=4.5V$ )	< 11.5m $\Omega$

100% UIS Tested  
100%  $R_g$  Tested



DFN5x6



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AON6370	DFN 5x6	Tape & Reel	3000

### Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$T_C=25^\circ\text{C}$	47	A
Current		29	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	90	
Continuous Drain Current	$T_A=25^\circ\text{C}$	23	A
Current		18	
Avalanche Current <sup>C</sup>	$I_{AS}$	40	A
Avalanche energy $L=0.01\text{mH}$ <sup>C</sup>	$E_{AS}$	8	mJ
$V_{DS}$ Spike	10 $\mu\text{s}$	$V_{SPIKE}$	V
Power Dissipation <sup>B</sup>	$T_C=25^\circ\text{C}$	26	W
		10	
Power Dissipation <sup>A</sup>	$T_A=25^\circ\text{C}$	6.2	W
		4	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$t \leq 10\text{s}$	$R_{\theta JA}$	15	°C/W
Maximum Junction-to-Ambient <sup>A,D</sup>	Steady-State		40	°C/W
Maximum Junction-to-Case	Steady-State	$R_{\theta JC}$	3.8	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$\text{ID}=250\mu\text{A}, \text{VGS}=0\text{V}$	30			V
$\text{I}_{\text{DSS}}$	Zero Gate Voltage Drain Current	$\text{V}_{\text{DS}}=30\text{V}, \text{V}_{\text{GS}}=0\text{V}$	$T_J=55^\circ\text{C}$		1	$\mu\text{A}$
					5	
$\text{I}_{\text{GSS}}$	Gate-Body leakage current	$\text{V}_{\text{DS}}=0\text{V}, \text{V}_{\text{GS}}=\pm 20\text{V}$			$\pm 100$	nA
$\text{V}_{\text{GS(th)}}$	Gate Threshold Voltage	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_{\text{D}}=250\mu\text{A}$	1.4	1.8	2.2	V
$\text{R}_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_{\text{D}}=20\text{A}$		5.8	7.2	$\text{m}\Omega$
			$T_J=125^\circ\text{C}$		8.7	
		$\text{V}_{\text{GS}}=4.5\text{V}, \text{I}_{\text{D}}=20\text{A}$			9	11.5
$\text{g}_{\text{FS}}$	Forward Transconductance	$\text{V}_{\text{DS}}=5\text{V}, \text{I}_{\text{D}}=20\text{A}$			62	S
$\text{V}_{\text{SD}}$	Diode Forward Voltage	$\text{I}_{\text{S}}=1\text{A}, \text{V}_{\text{GS}}=0\text{V}$		0.71	1	V
$\text{I}_{\text{S}}$	Maximum Body-Diode Continuous Current				30	A
<b>DYNAMIC PARAMETERS</b>						
$\text{C}_{\text{iss}}$	Input Capacitance	$\text{V}_{\text{GS}}=0\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{f}=1\text{MHz}$		840		pF
$\text{C}_{\text{oss}}$	Output Capacitance			330		pF
$\text{C}_{\text{rss}}$	Reverse Transfer Capacitance			50		pF
$\text{R}_{\text{g}}$	Gate resistance	$\text{f}=1\text{MHz}$	0.6	1.2	1.8	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$\text{Q}_{\text{g}}(10\text{V})$	Total Gate Charge	$\text{V}_{\text{GS}}=10\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{I}_{\text{D}}=20\text{A}$		13		nC
$\text{Q}_{\text{g}}(4.5\text{V})$	Total Gate Charge			6.2		nC
$\text{Q}_{\text{gs}}$	Gate Source Charge			2.5		nC
$\text{Q}_{\text{gd}}$	Gate Drain Charge			3.5		nC
$\text{Q}_{\text{gs}}$	Gate Source Charge			2.5		nC
$\text{Q}_{\text{gd}}$	Gate Drain Charge			3.5		nC
$\text{t}_{\text{D(on)}}$	Turn-On Delay Time	$\text{V}_{\text{GS}}=10\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{R}_{\text{L}}=0.75\Omega, \text{R}_{\text{GEN}}=3\Omega$		5.5		ns
$\text{t}_{\text{r}}$	Turn-On Rise Time			3		ns
$\text{t}_{\text{D(off)}}$	Turn-Off Delay Time			17		ns
$\text{t}_{\text{f}}$	Turn-Off Fall Time			3		ns
$\text{t}_{\text{rr}}$	Body Diode Reverse Recovery Time	$\text{I}_{\text{F}}=20\text{A}, \text{dI}/\text{dt}=500\text{A}/\mu\text{s}$		11		ns
$\text{Q}_{\text{rr}}$	Body Diode Reverse Recovery Charge	$\text{I}_{\text{F}}=20\text{A}, \text{dI}/\text{dt}=500\text{A}/\mu\text{s}$		18		nC

A. The value of  $\text{R}_{\text{BJA}}$  is measured with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The Power dissipation  $P_{\text{DSM}}$  is based on  $\text{R}_{\text{BJA}} \leq 10\text{s}$  and the maximum allowed junction temperature of  $150^\circ\text{C}$ . The value in any given application depends on the user's specific board design.

B. The power dissipation  $P_D$  is based on  $T_{\text{J(MAX)}}=150^\circ\text{C}$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature  $T_{\text{J(MAX)}}=150^\circ\text{C}$ .

D. The  $\text{R}_{\text{BJA}}$  is the sum of the thermal impedance from junction to case  $\text{R}_{\text{BJC}}$  and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300 $\mu\text{s}$  pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{\text{J(MAX)}}=150^\circ\text{C}$ . The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ .

I. For application requiring slow >1ms turn-on/turn-off, please consult AOS FAE for proper product selection.

THIS PRODUCT HAS BEEN DESIGNED AND QUALIFIED FOR THE CONSUMER MARKET. APPLICATIONS OR USES AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS ARE NOT AUTHORIZED. AOS DOES NOT ASSUME ANY LIABILITY ARISING OUT OF SUCH APPLICATIONS OR USES OF ITS PRODUCTS. AOS RESERVES THE RIGHT TO IMPROVE PRODUCT DESIGN, FUNCTIONS AND RELIABILITY WITHOUT NOTICE.



## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

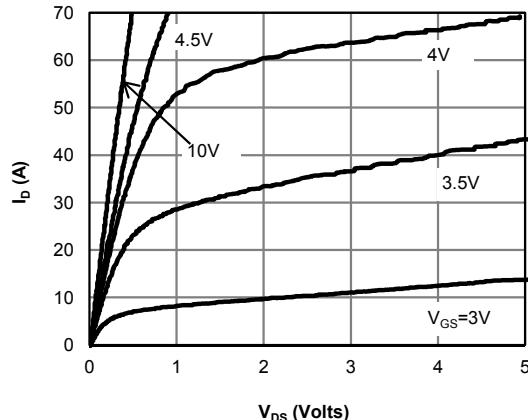


Figure 1: On-Region Characteristics (Note E)

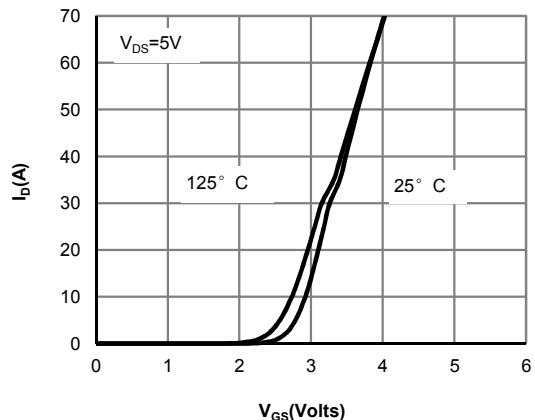


Figure 2: Transfer Characteristics (Note E)

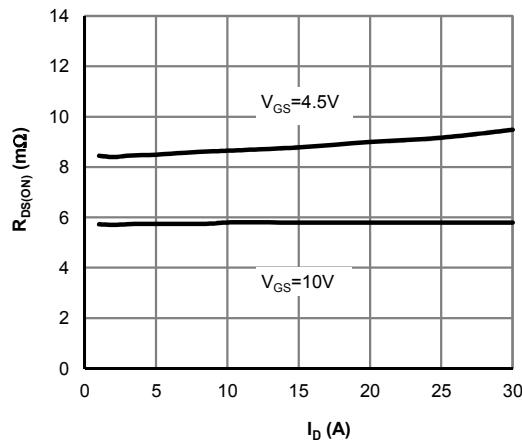


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

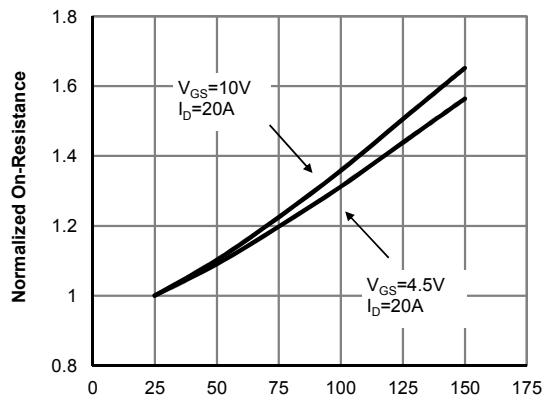


Figure 4: On-Resistance vs. Junction Temperature (Note E)

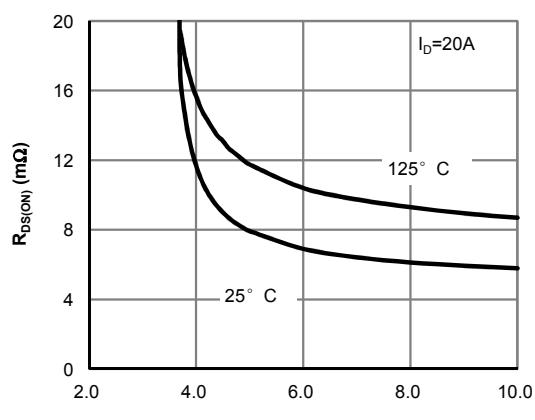


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

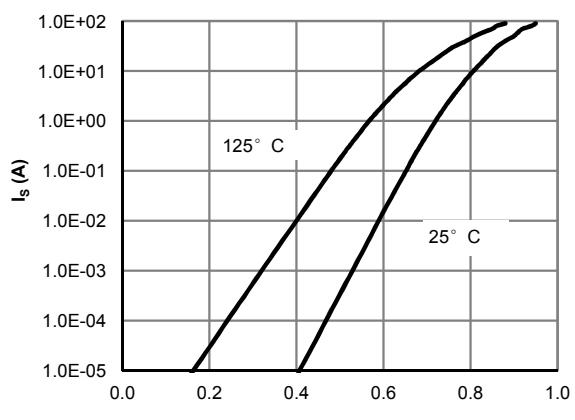


Figure 6: Body-Diode Characteristics (Note E)

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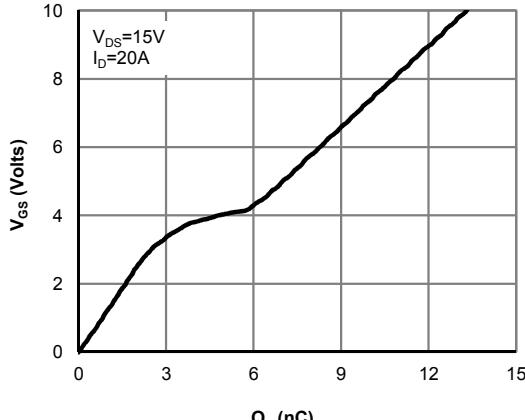


Figure 7: Gate-Charge Characteristics

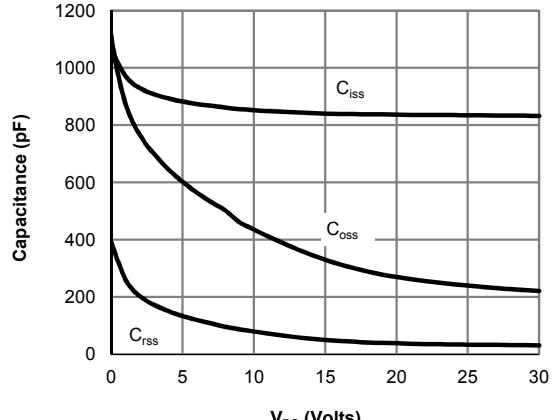


Figure 8: Capacitance Characteristics

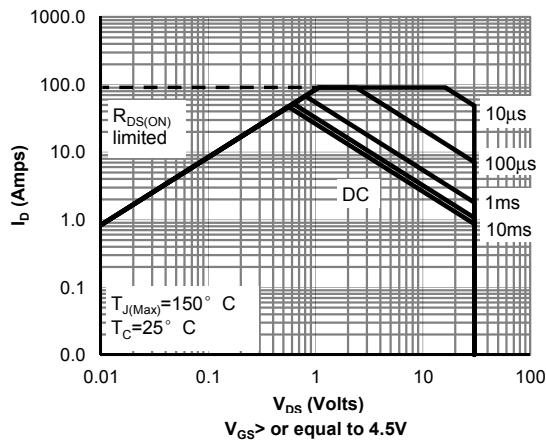


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

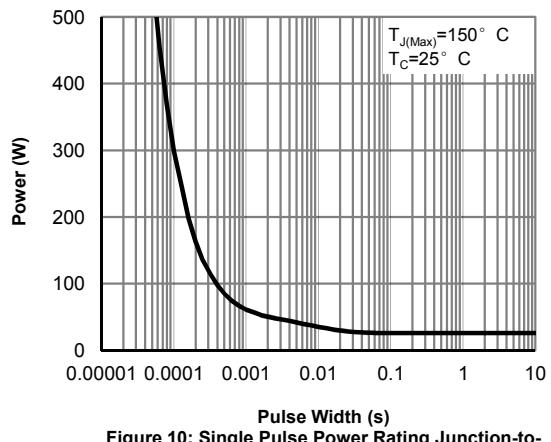


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

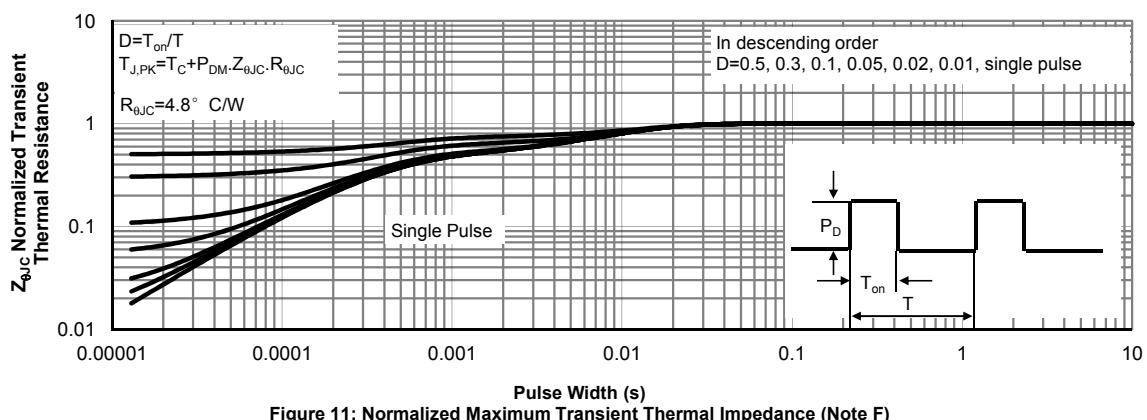


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)



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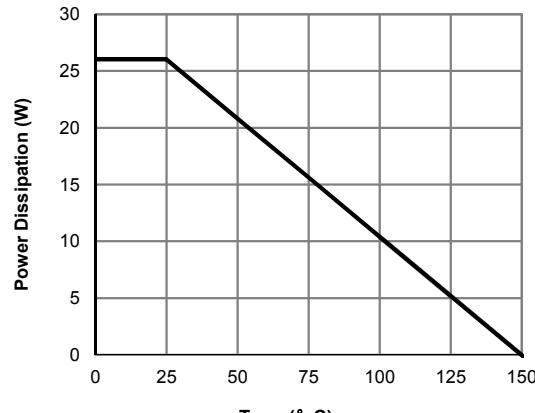


Figure 12: Power De-rating (Note F)

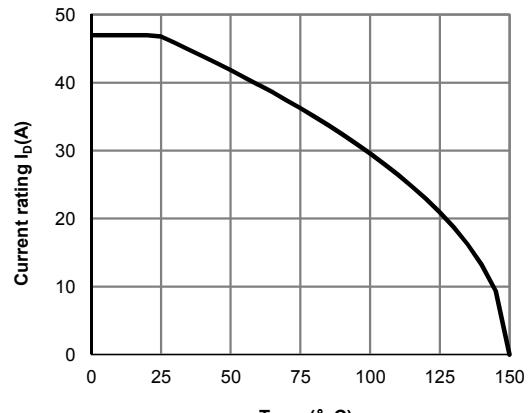


Figure 13: Current De-rating (Note F)

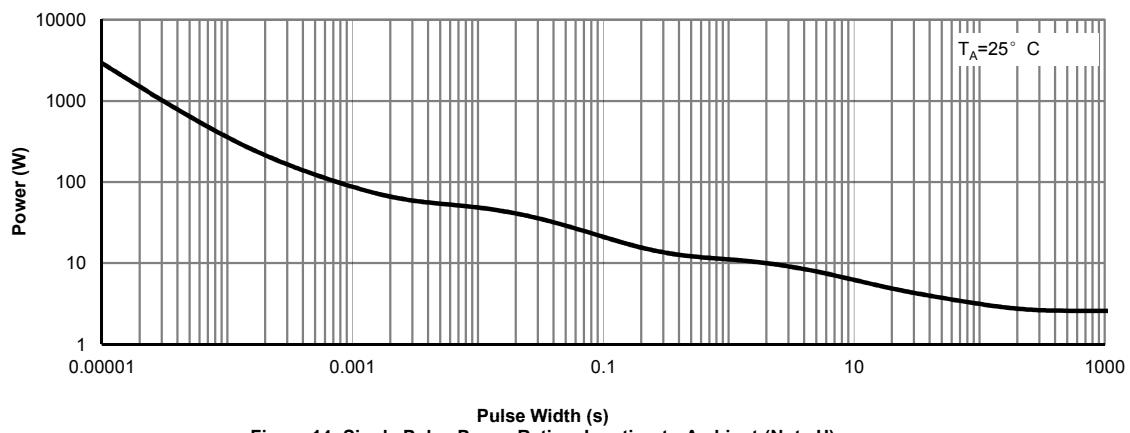


Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note H)

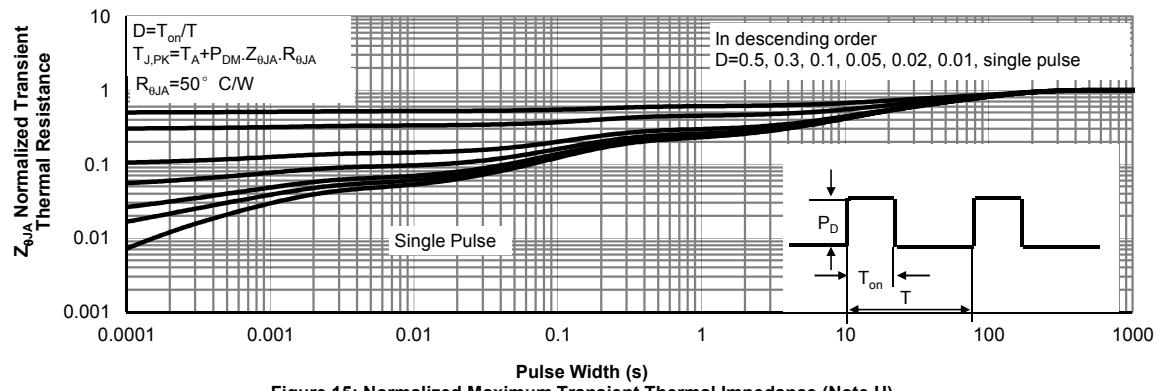
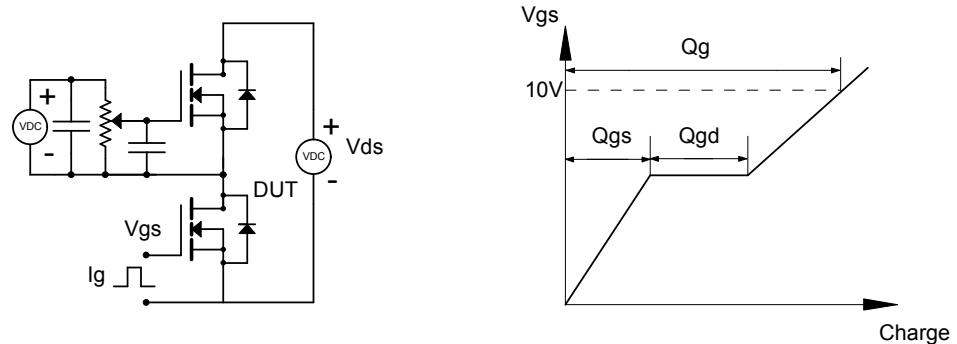
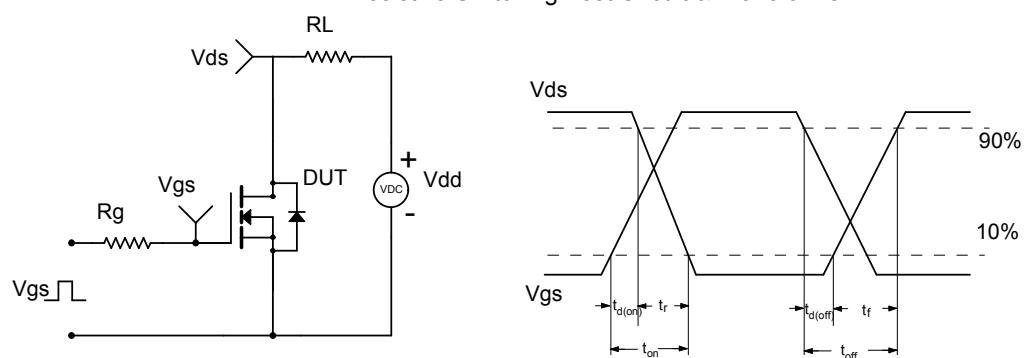


Figure 15: Normalized Maximum Transient Thermal Impedance (Note H)

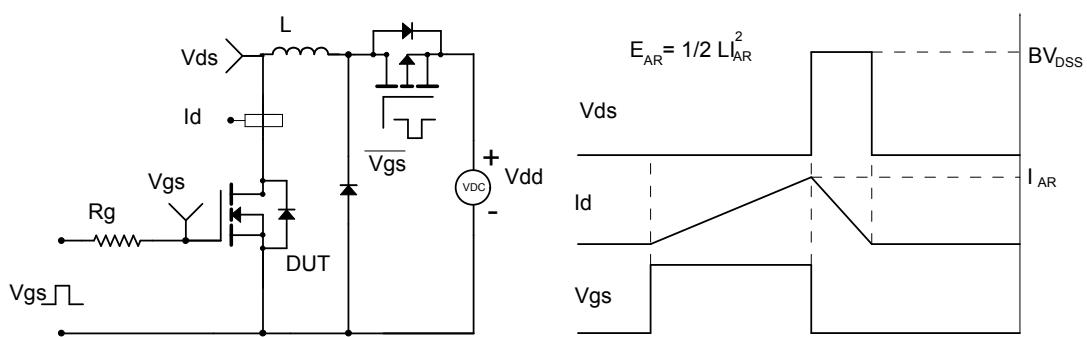
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

